

Fig. 1

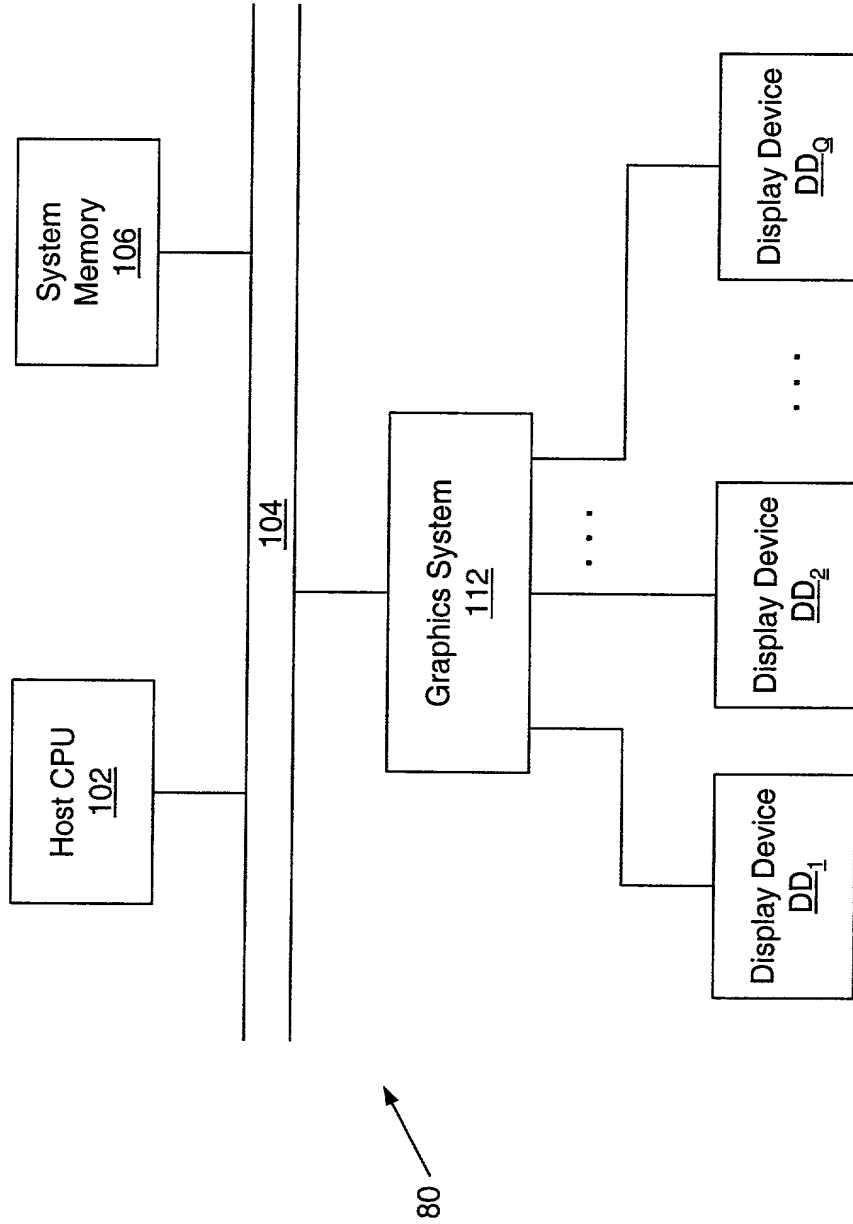


FIG. 2

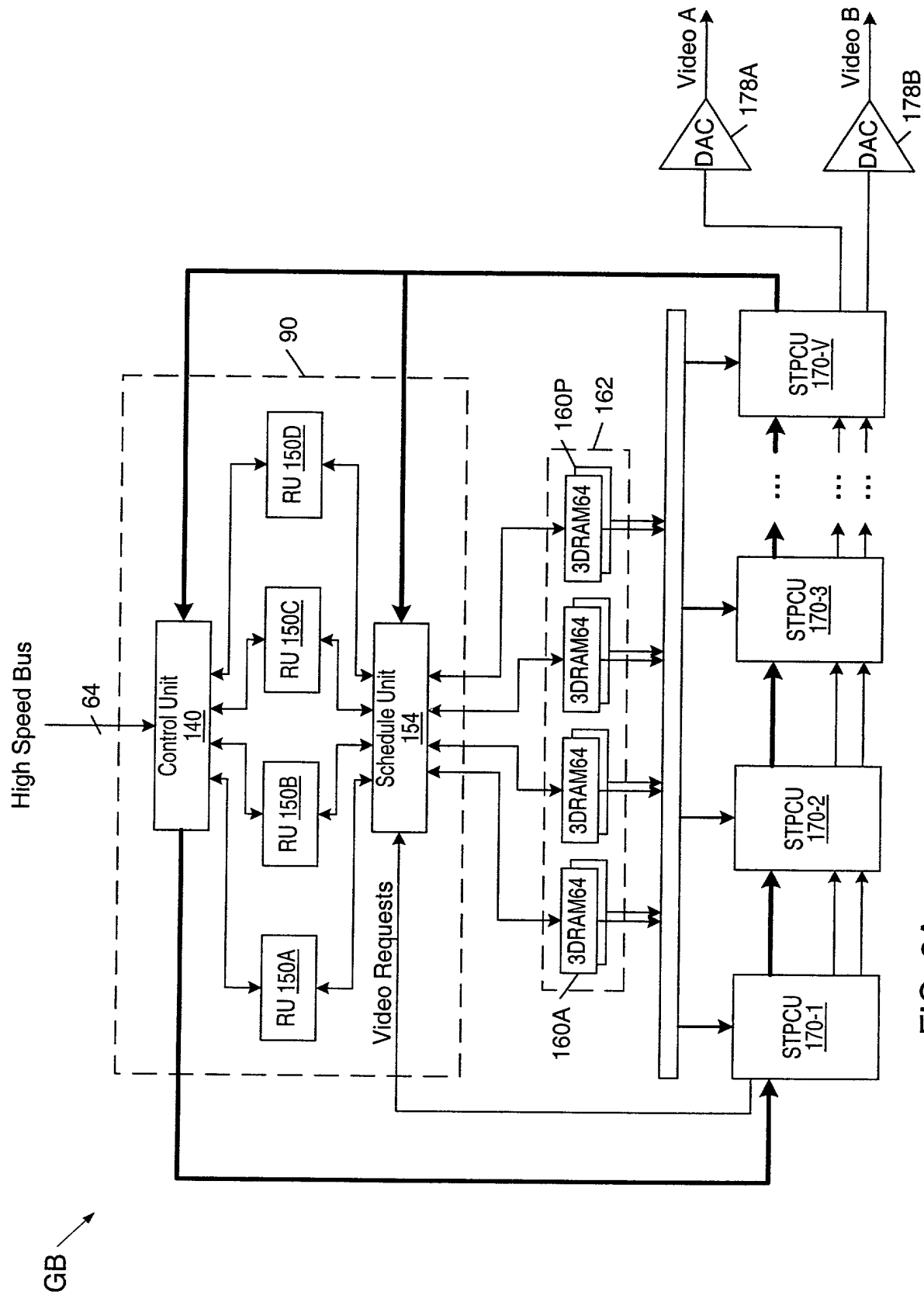


FIG. 3A

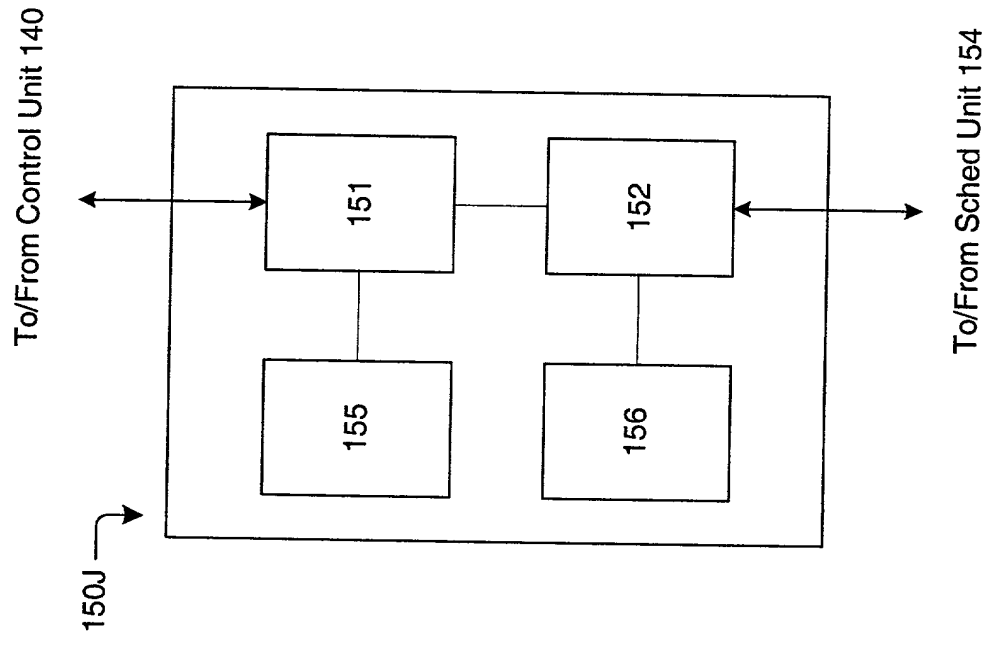


FIG. 3B

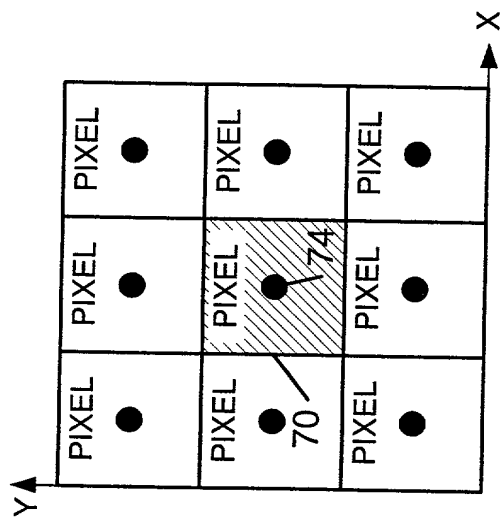


FIG. 4

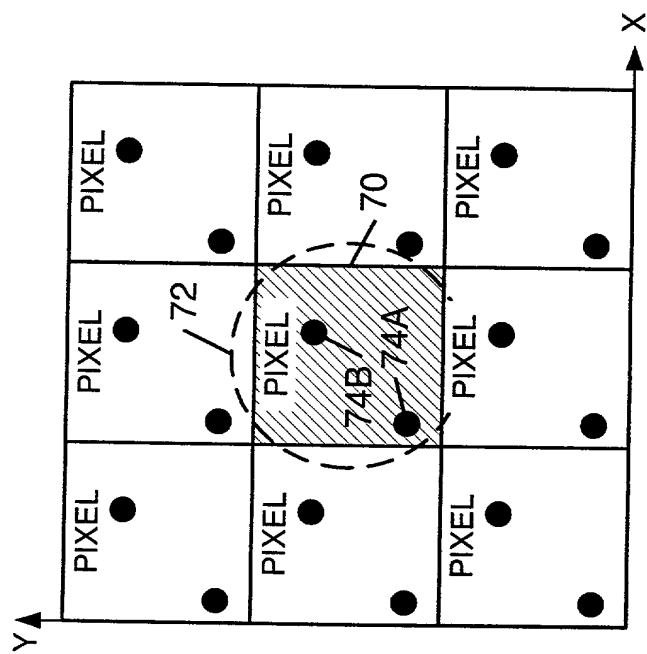


FIG. 5A

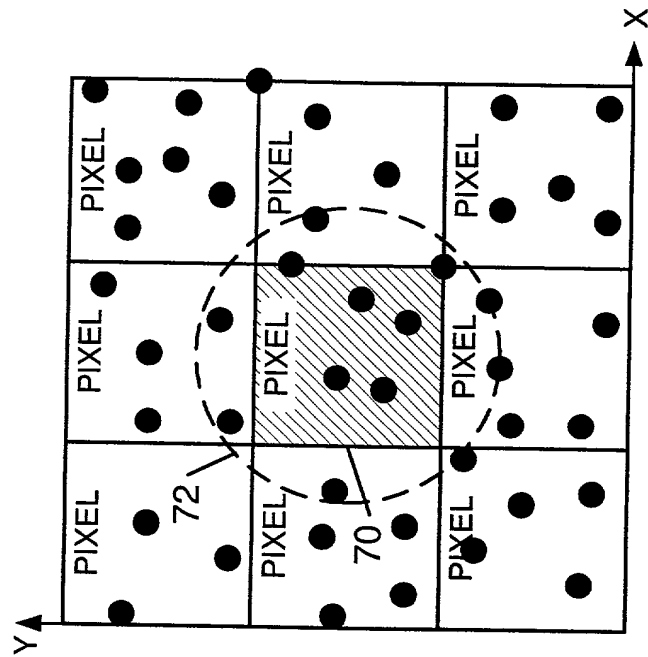


FIG. 5B

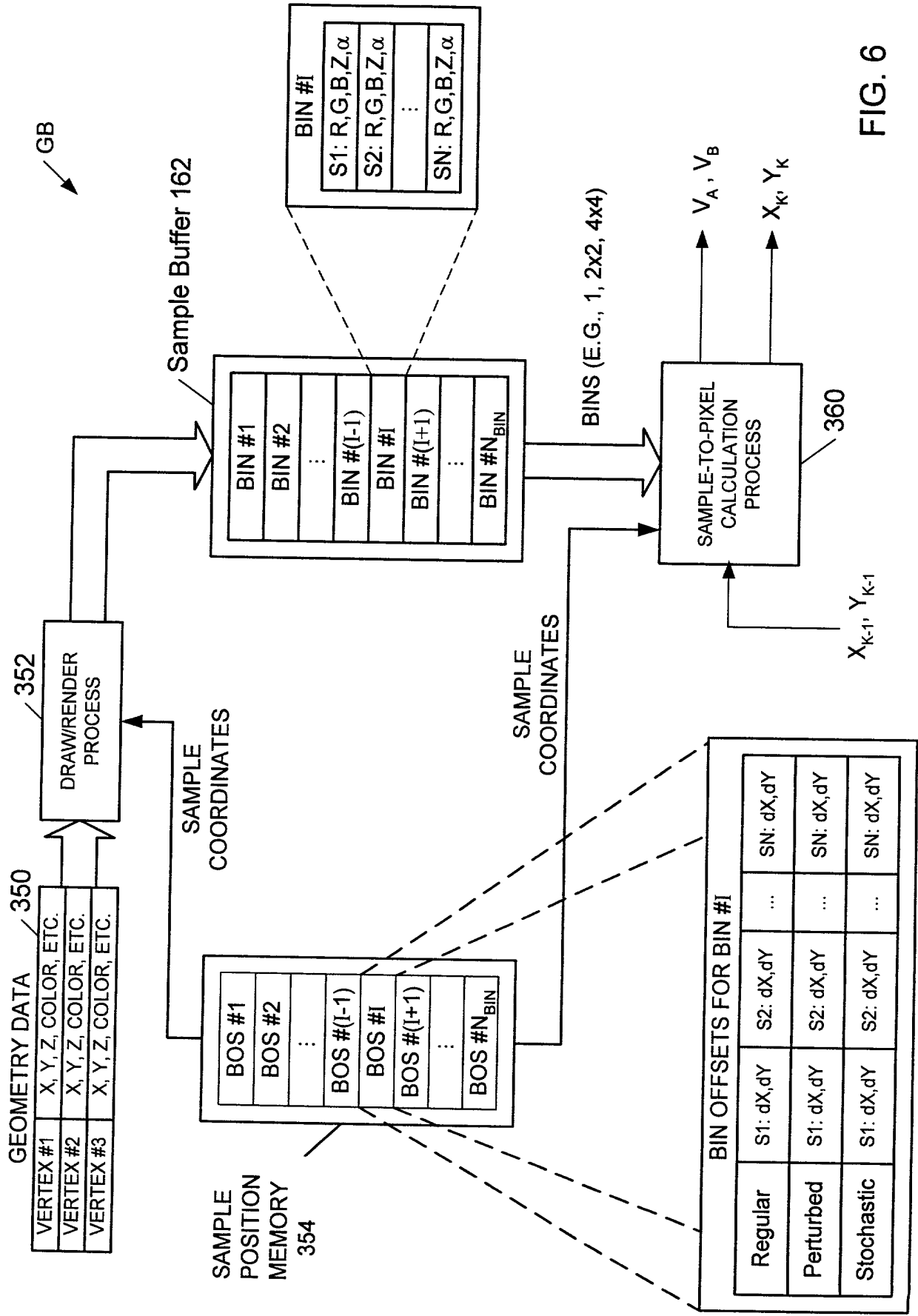


FIG. 6

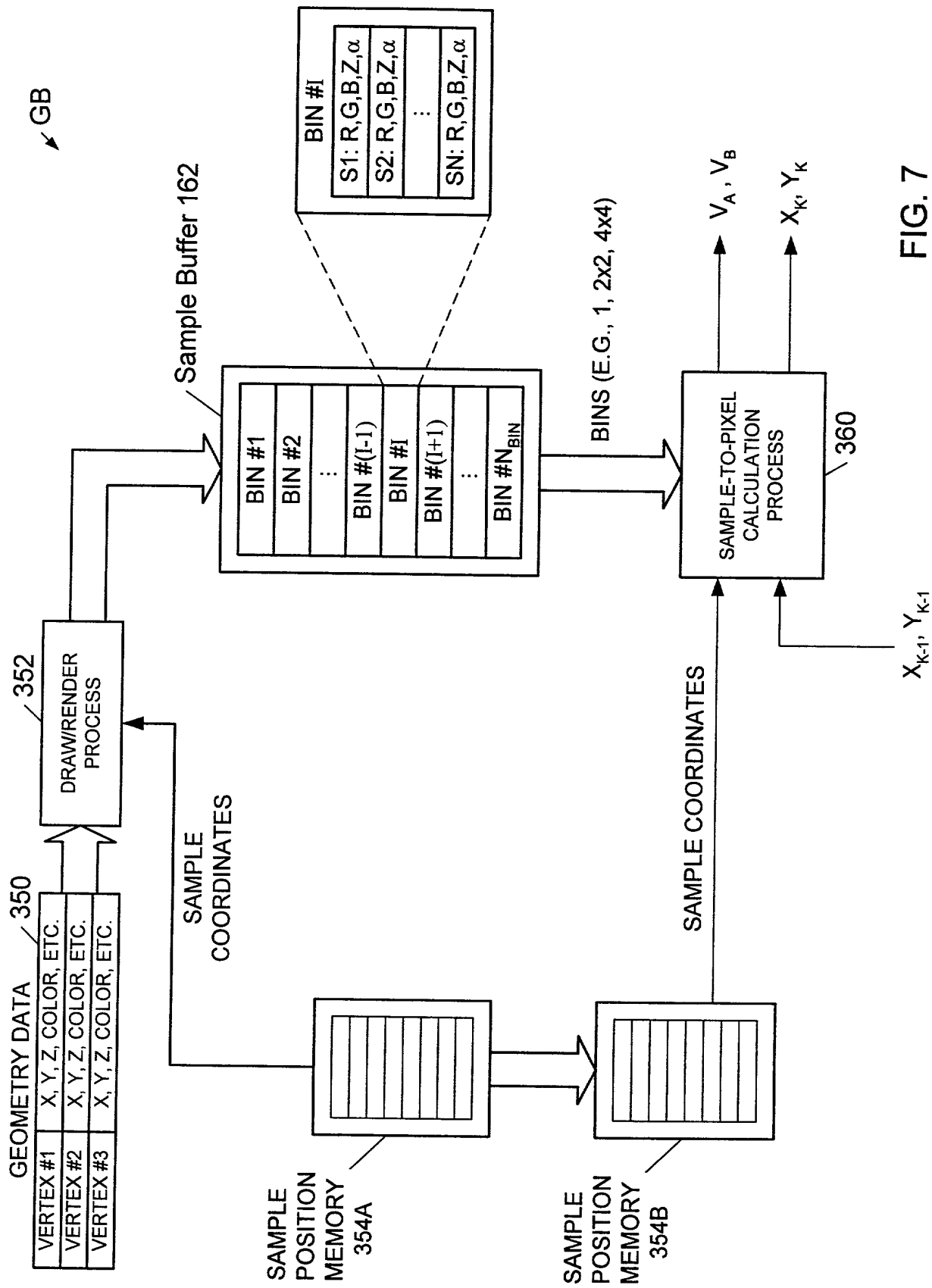
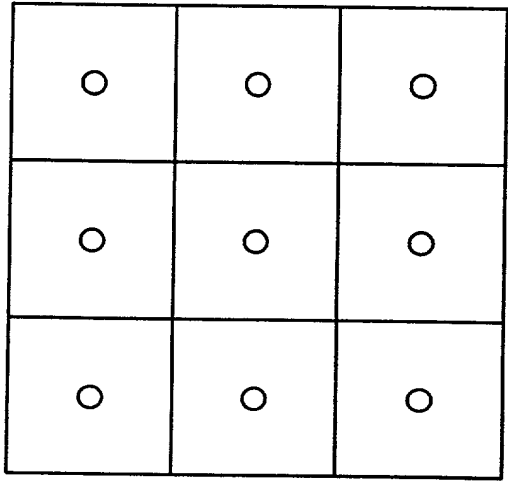
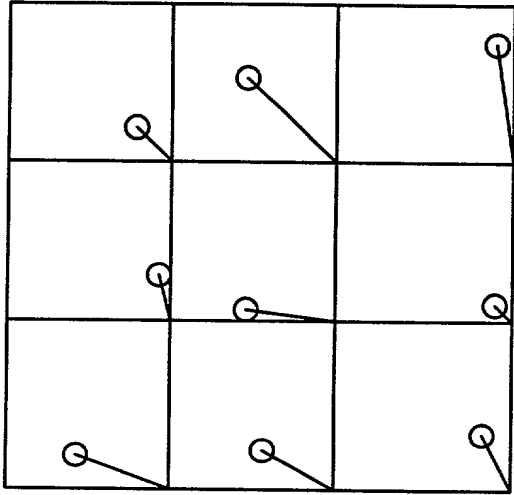


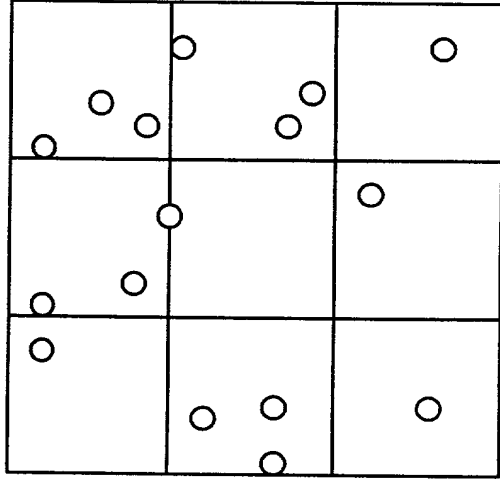
FIG. 7



Regular Sample Positioning  
190



Perturbed Regular Sample Positioning  
192



194

Stochastic Sample Positioning

FIG. 8



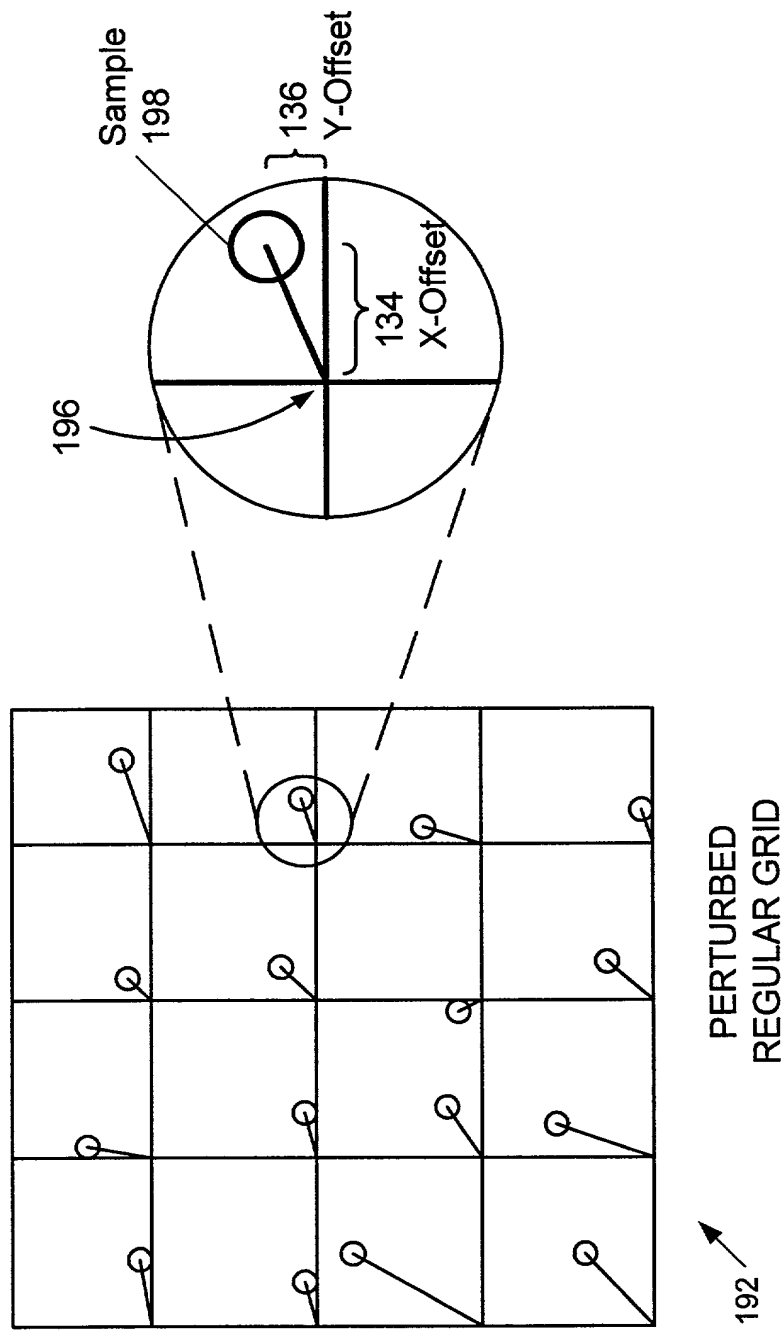


FIG. 9

PERTURBED  
REGULAR GRID  
192

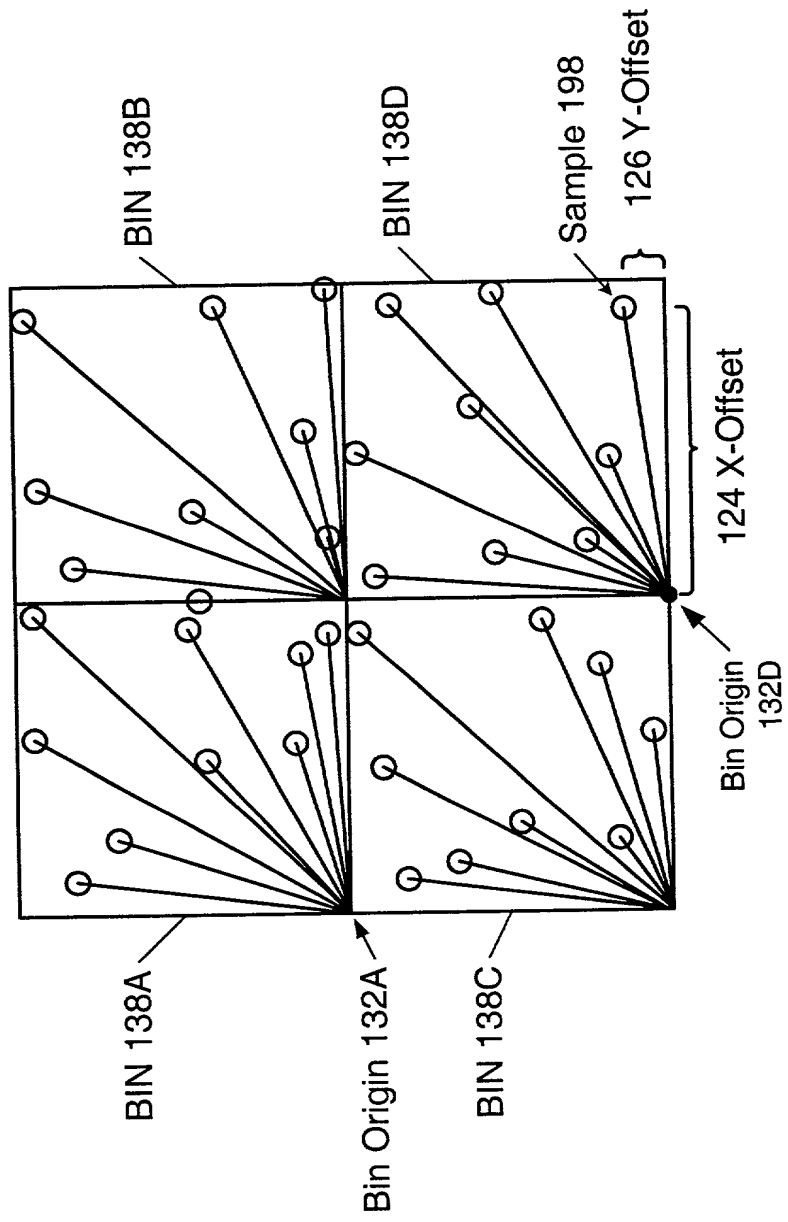


FIG. 10

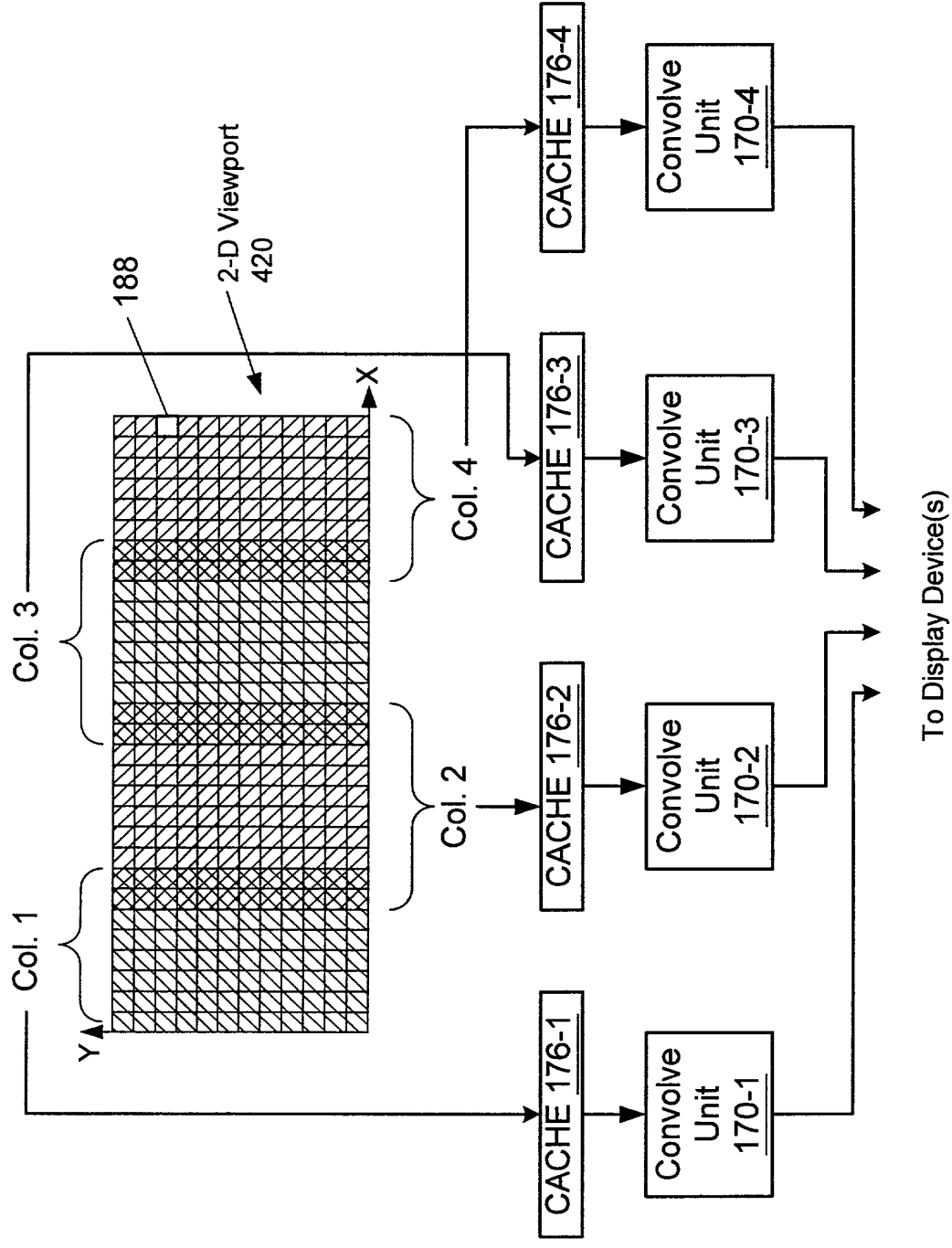


FIG. 11

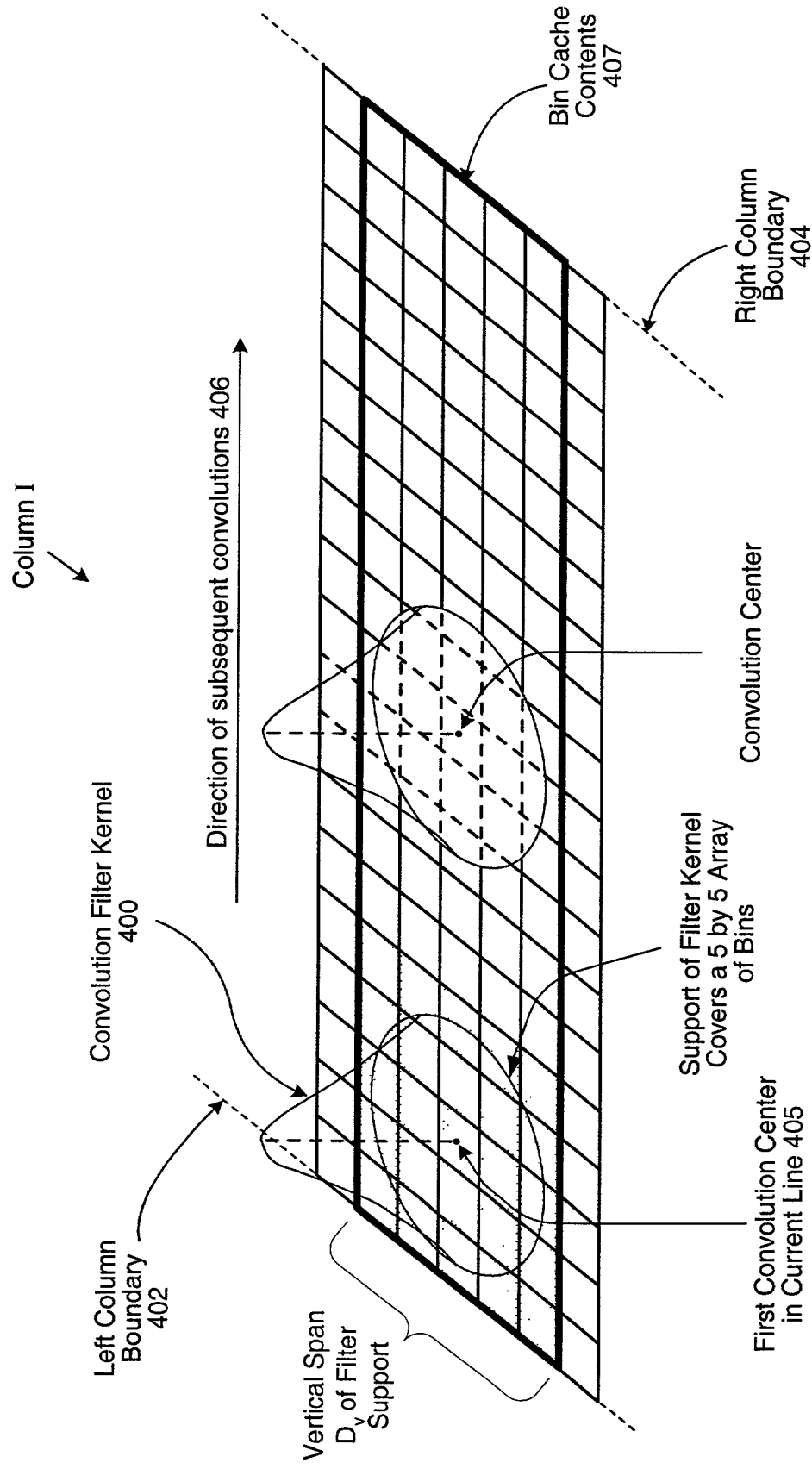


FIG. 12A

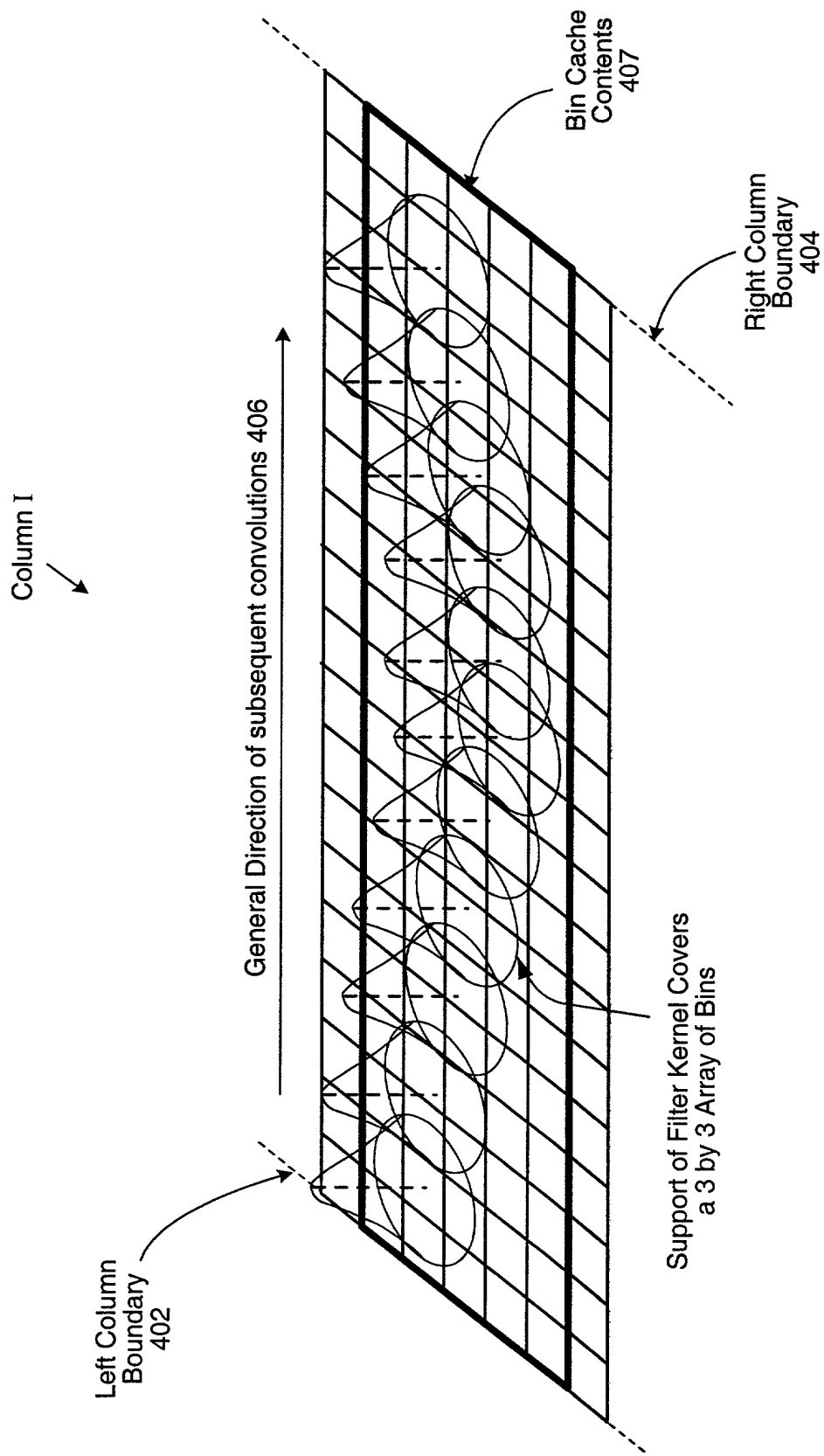


FIG. 12B

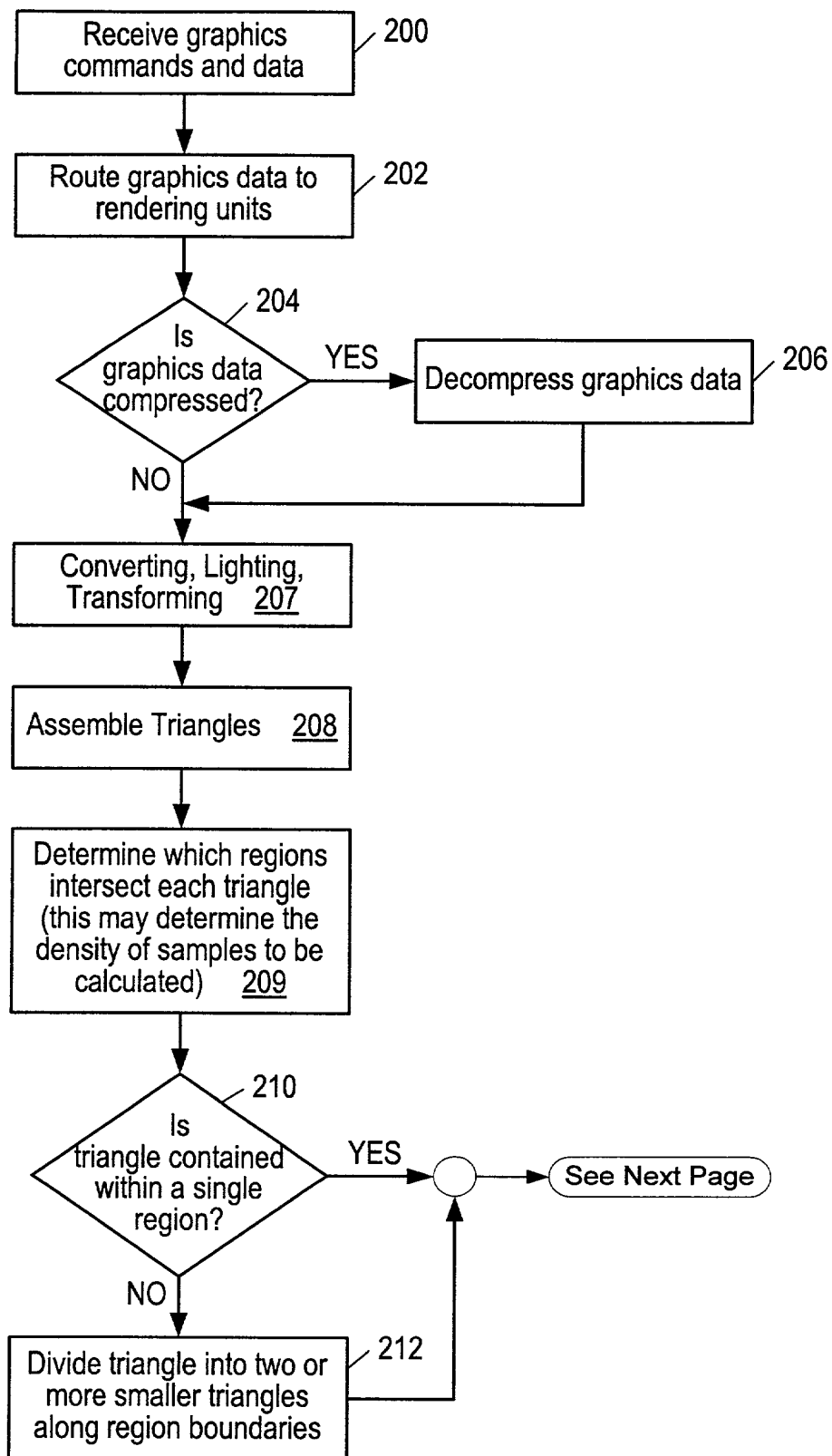


FIG. 13A

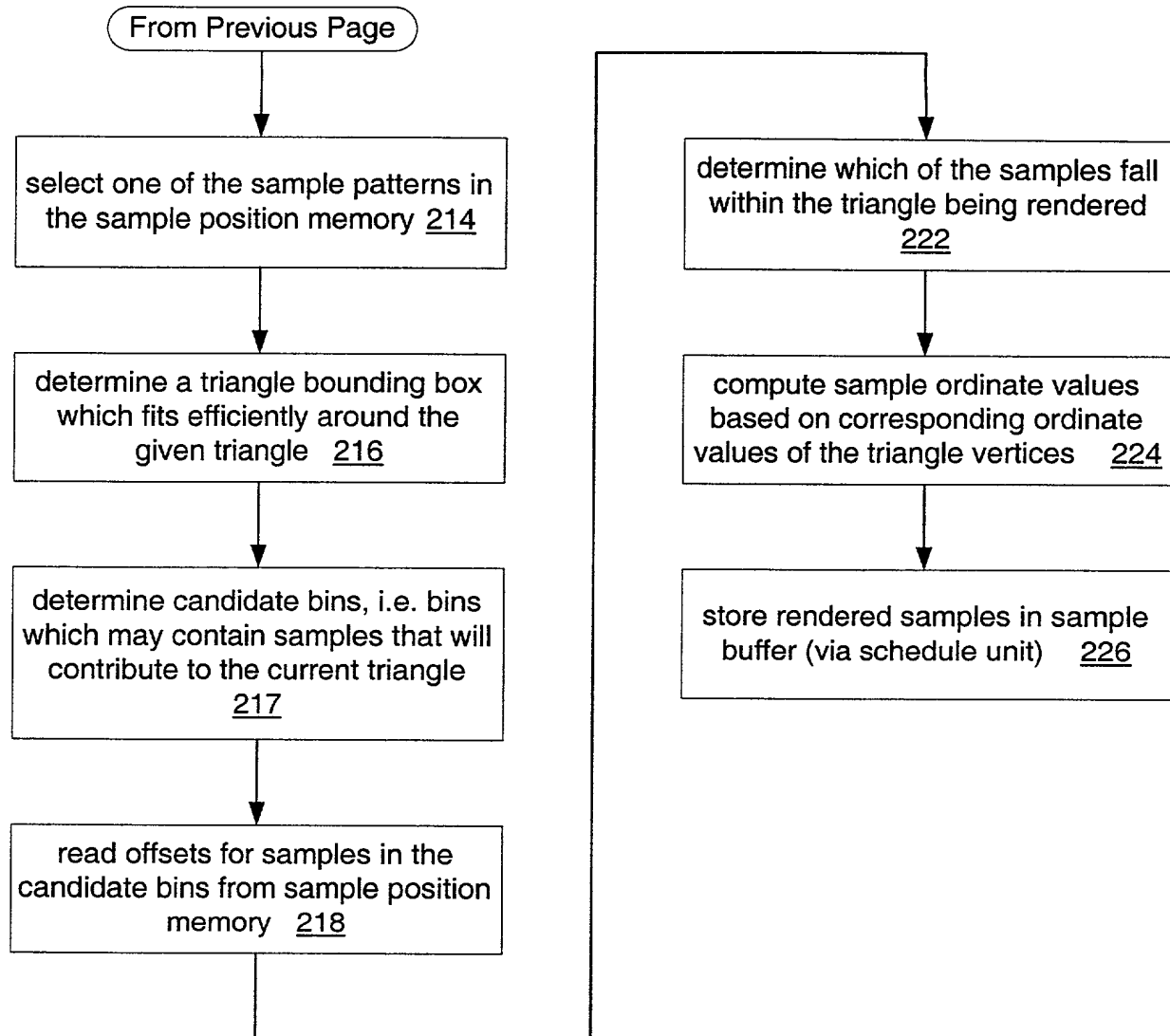


FIG. 13B

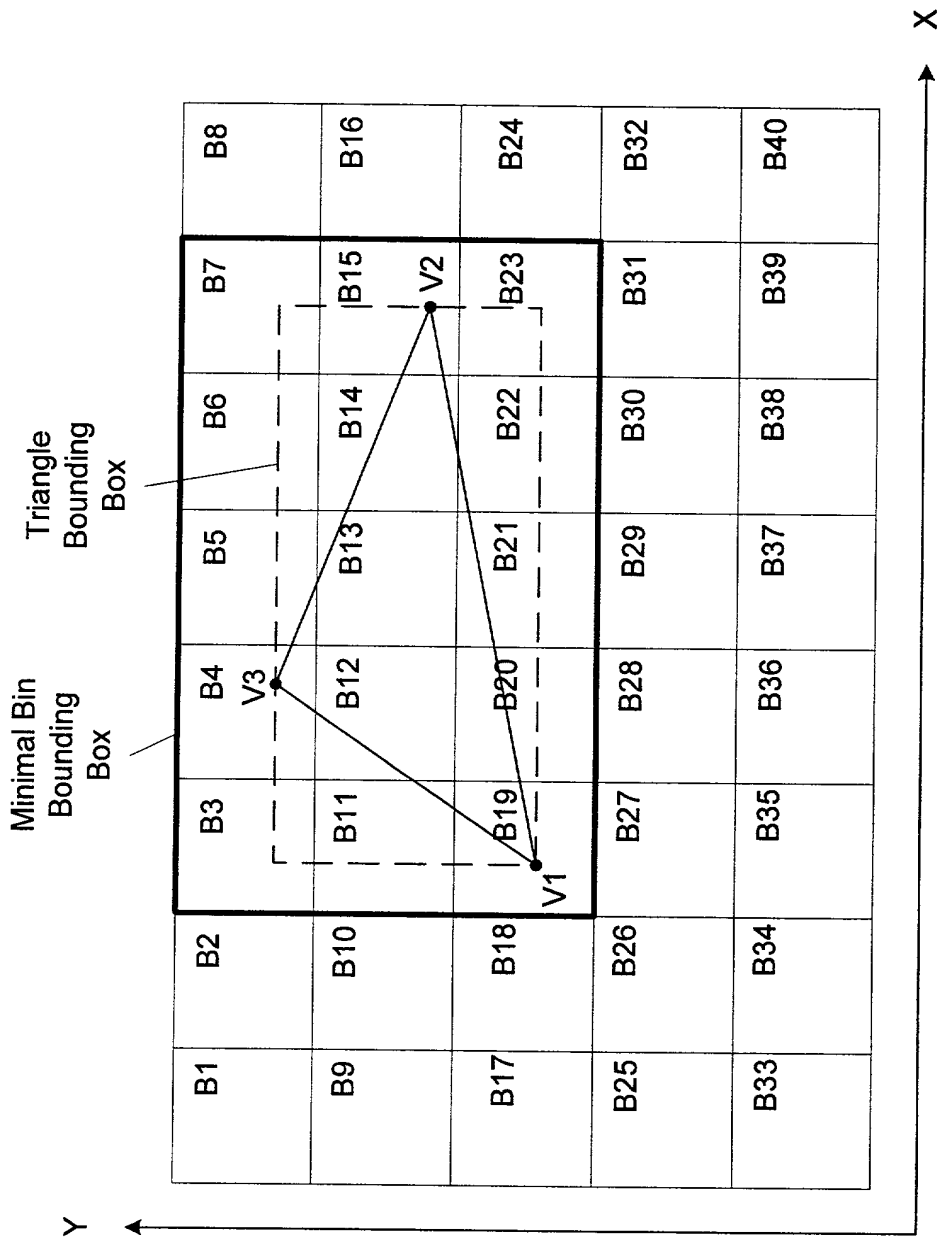


Fig. 13C



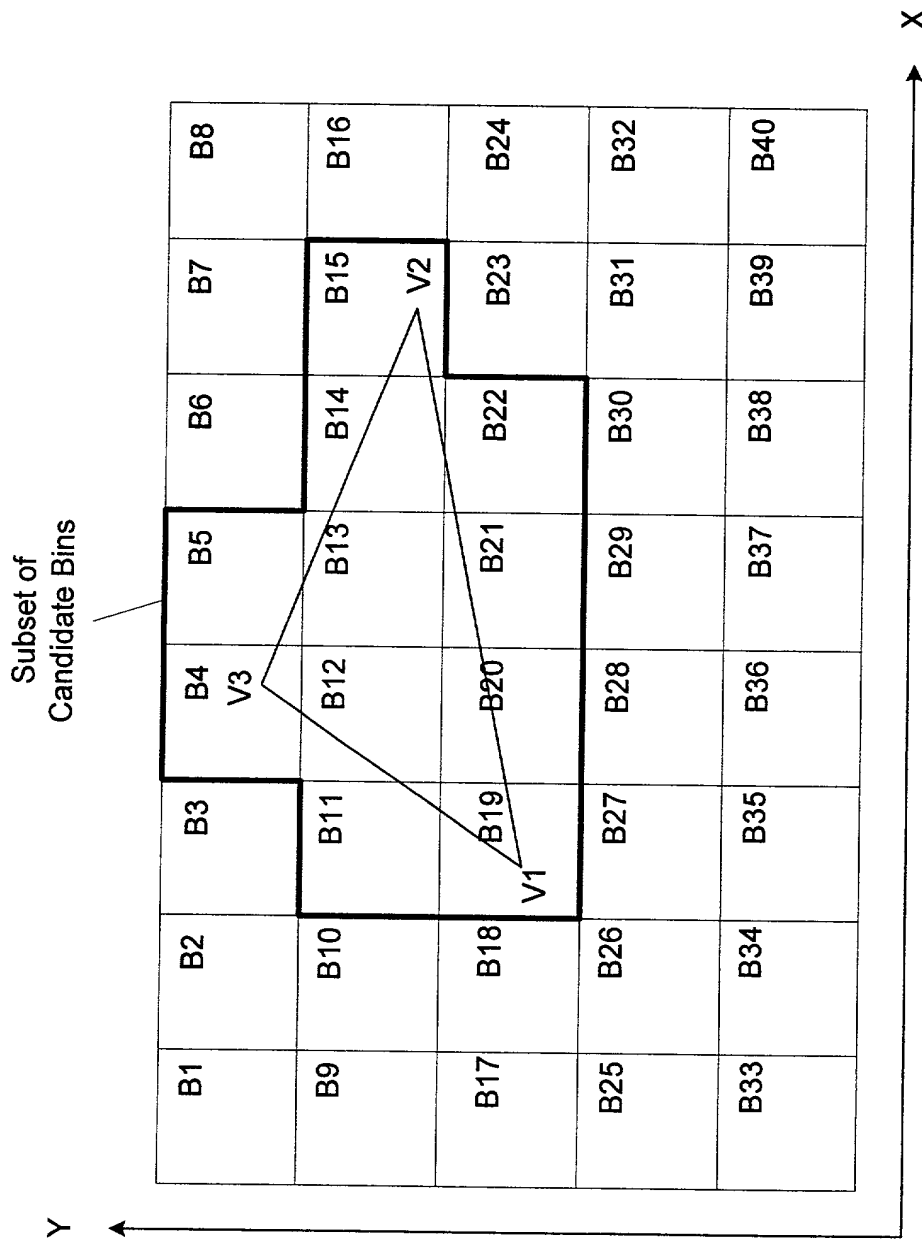


Fig. 13D

Bin Identifications

B3	B4	B5	B6	B7
B11	B12	B13	B14	B15
B19	B20	B21	B22	B22

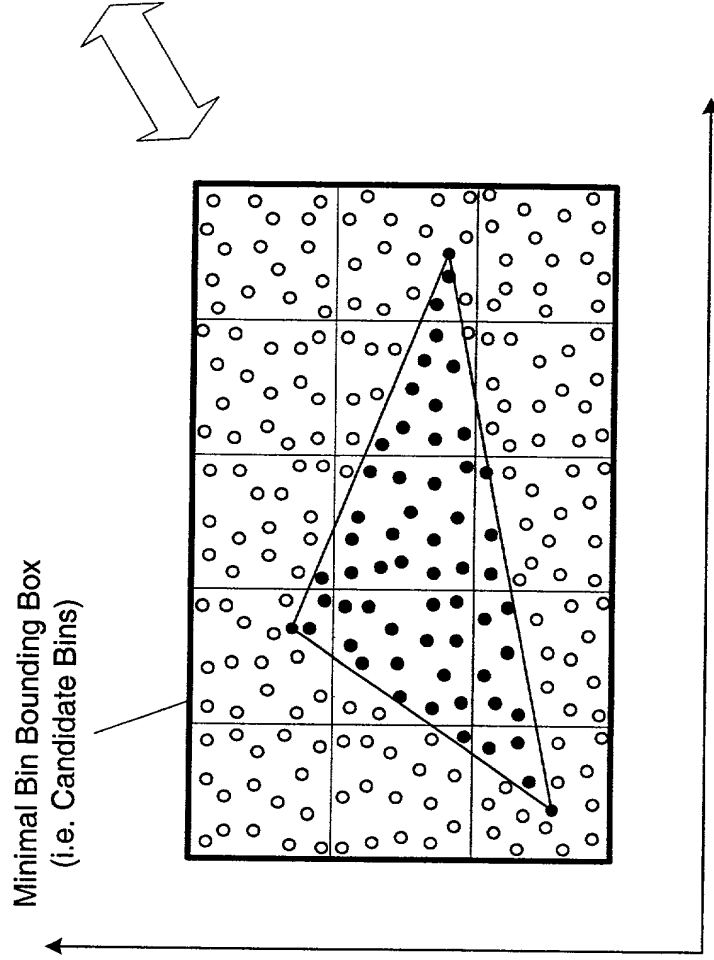


Fig. 13E

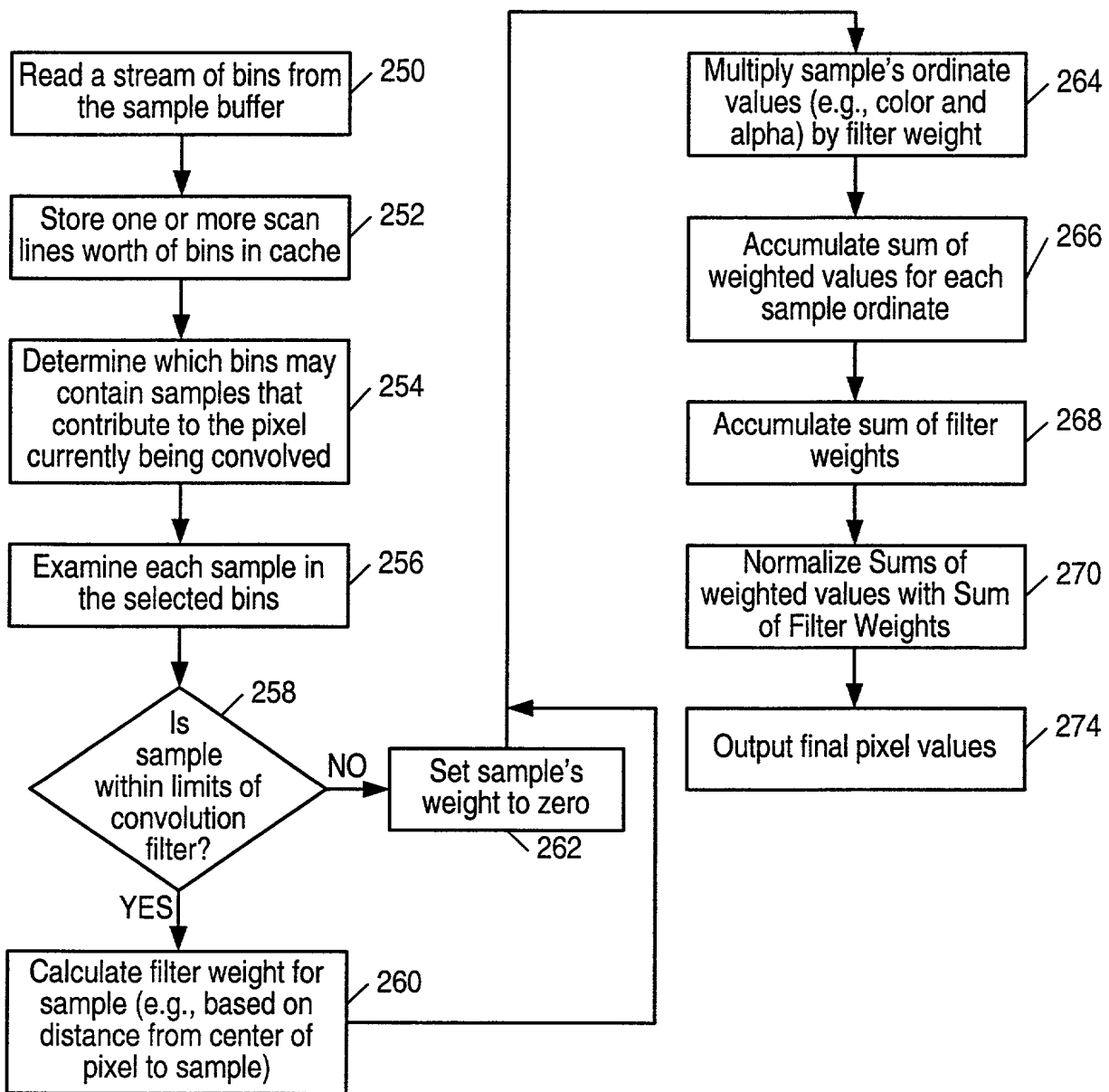


FIG. 14



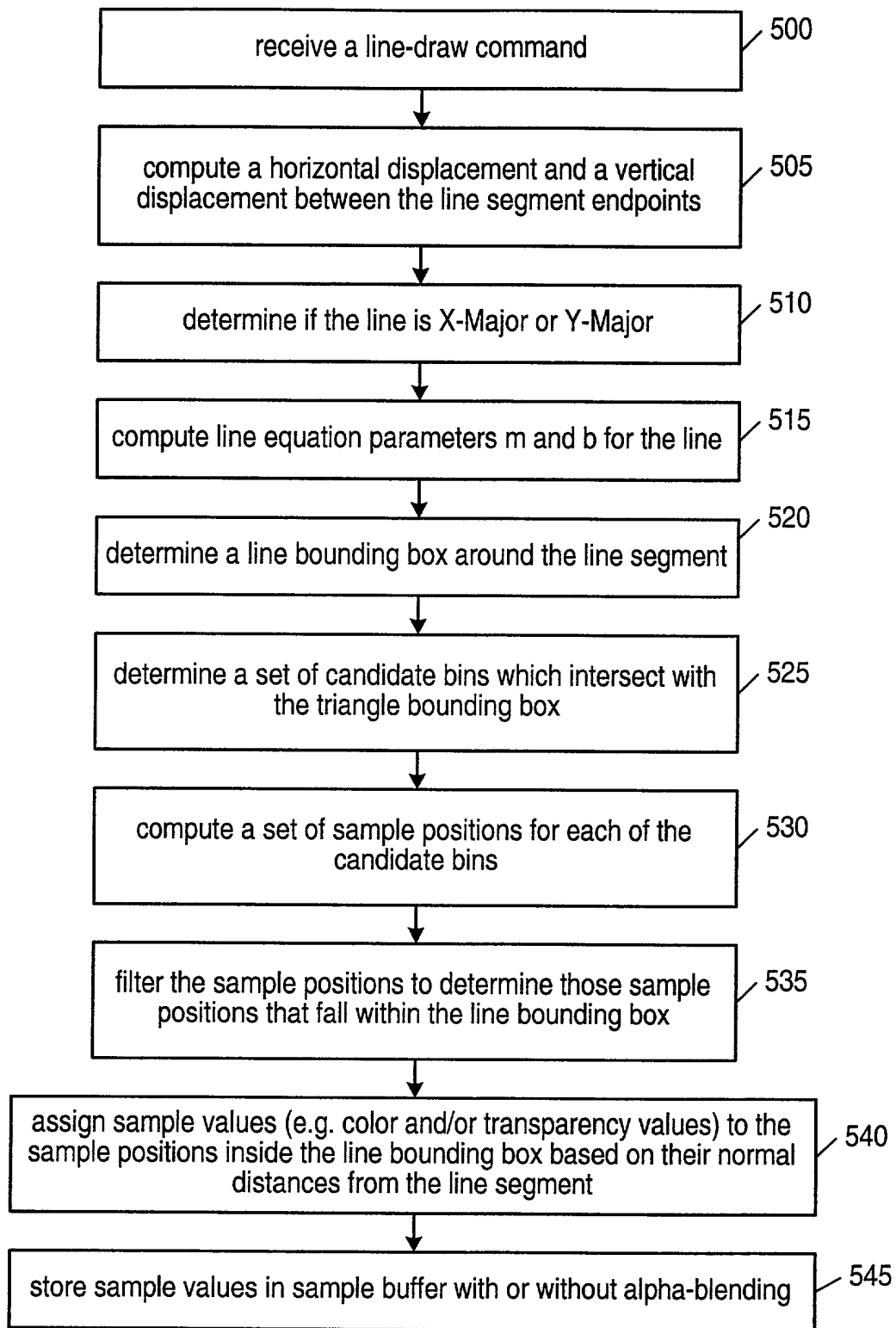


FIG. 16

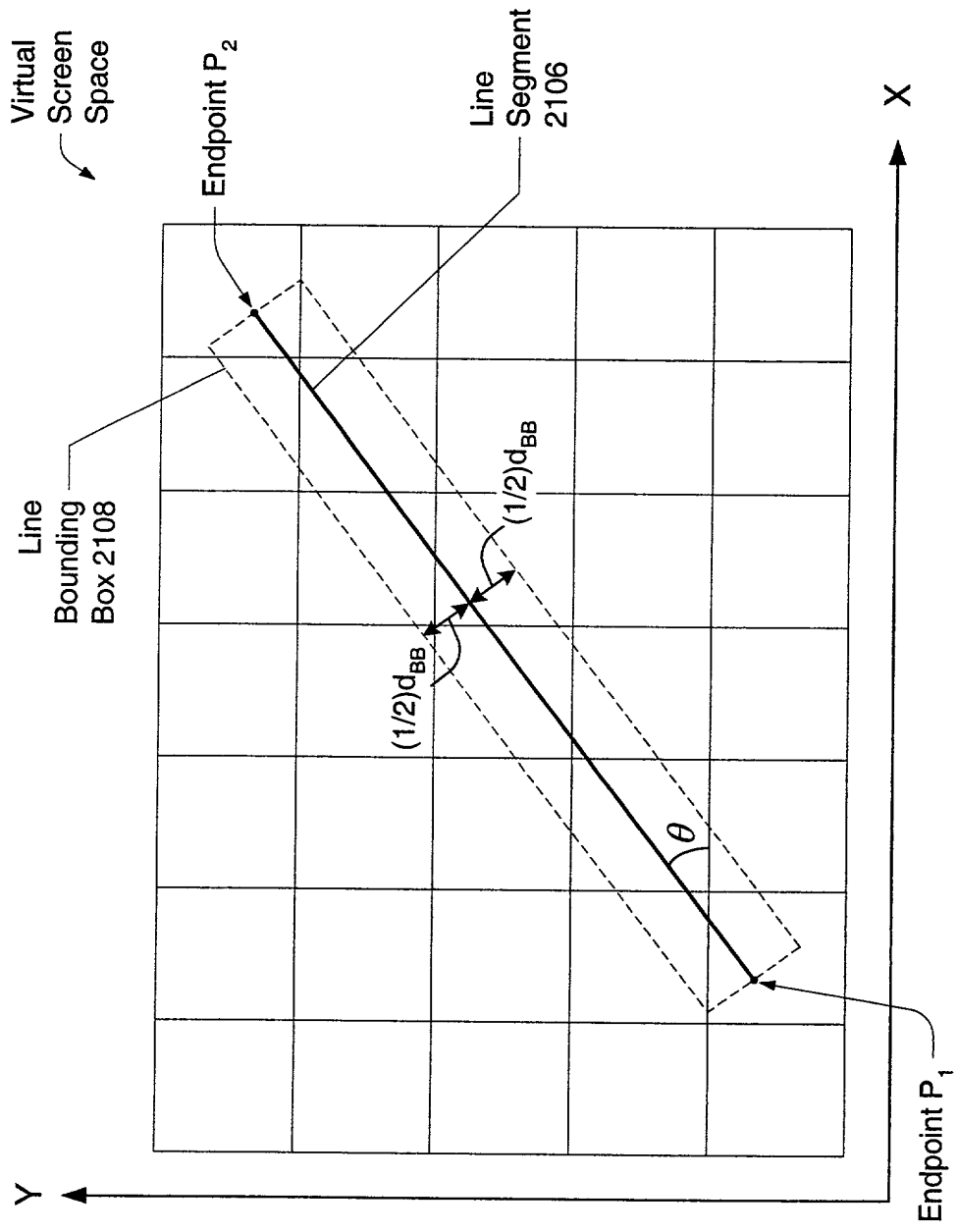


Fig. 17A

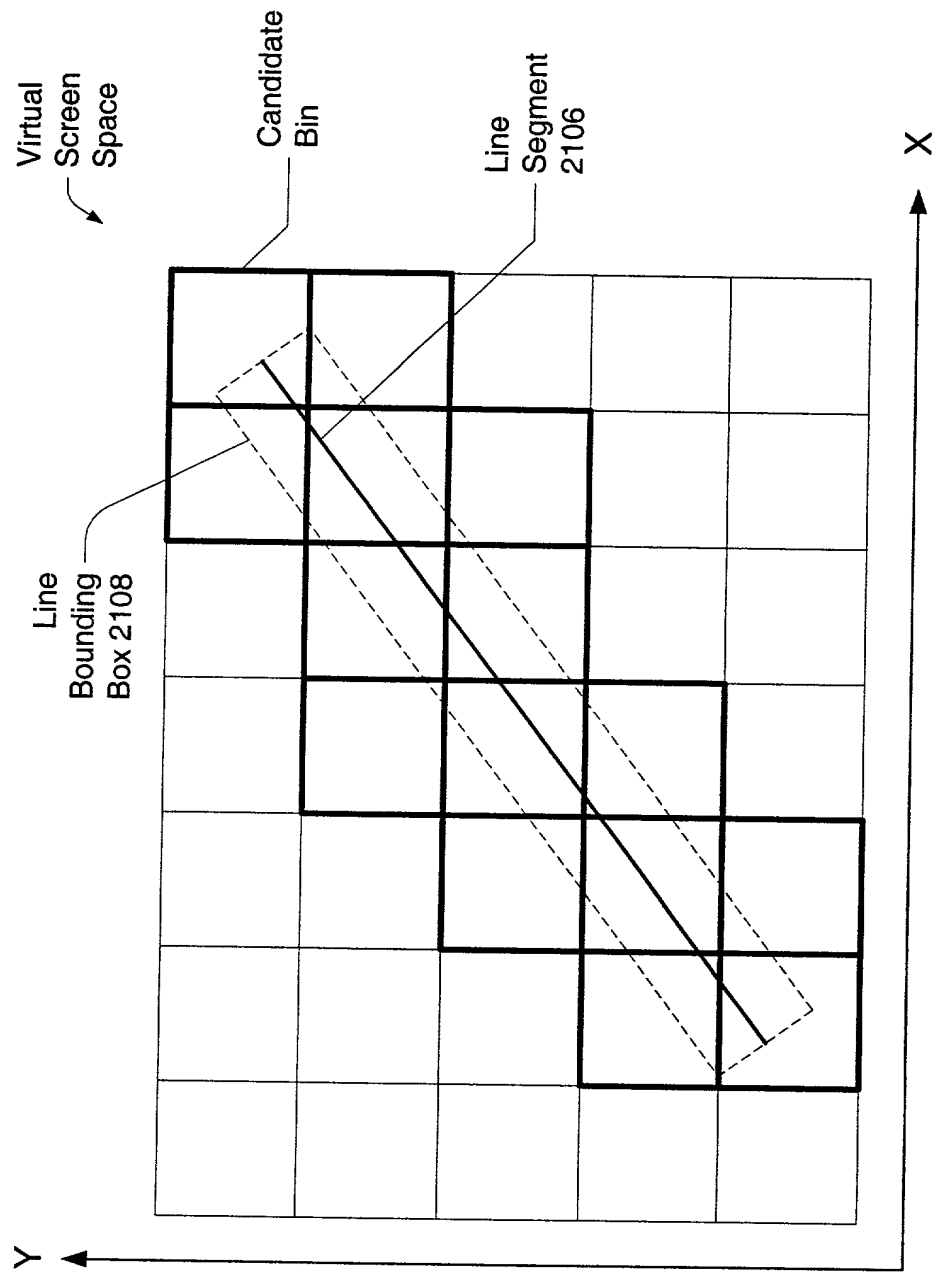


Fig. 17B

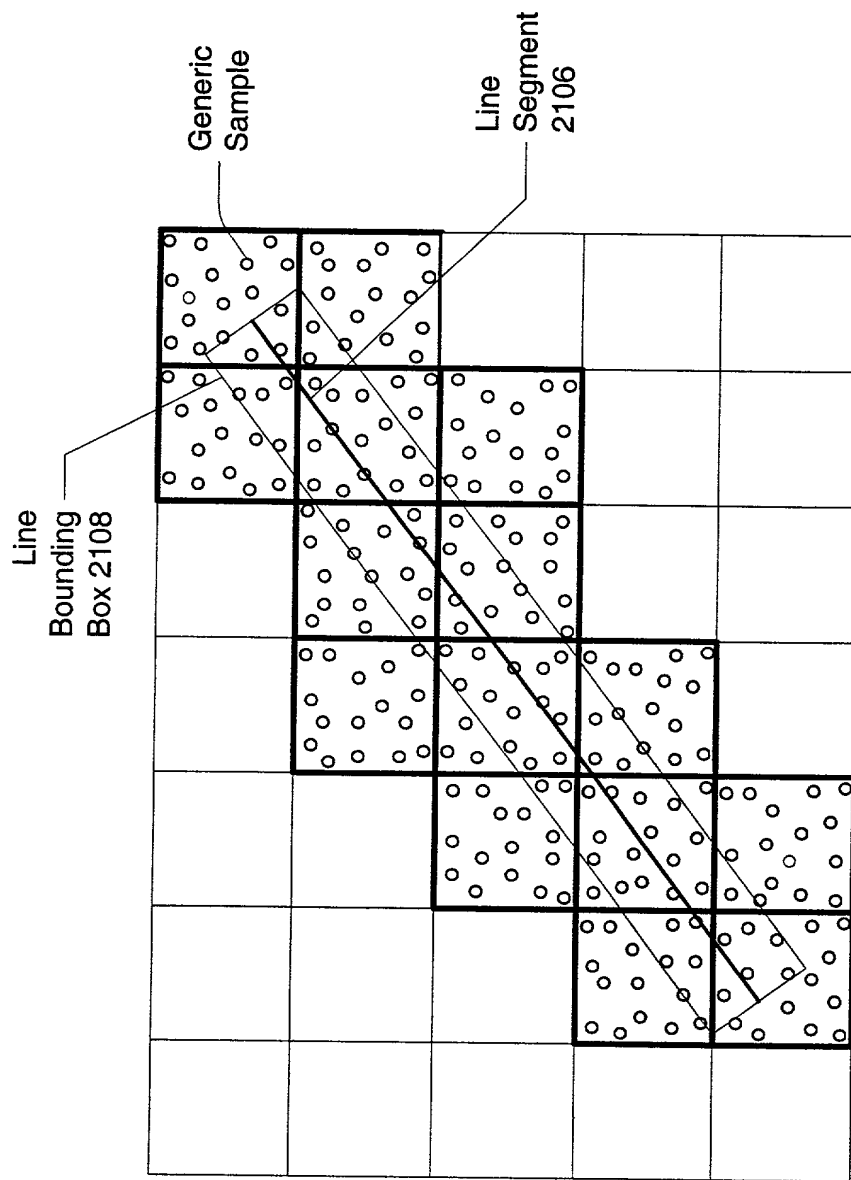


Fig. 17C





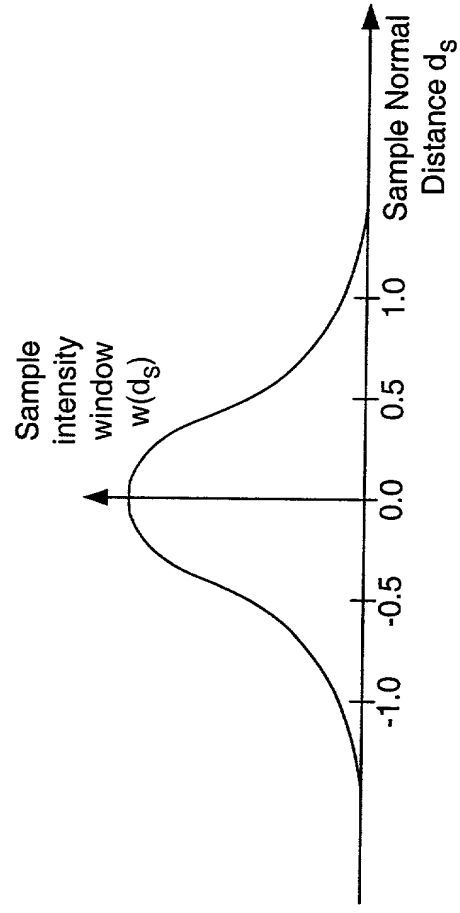


Fig. 17E

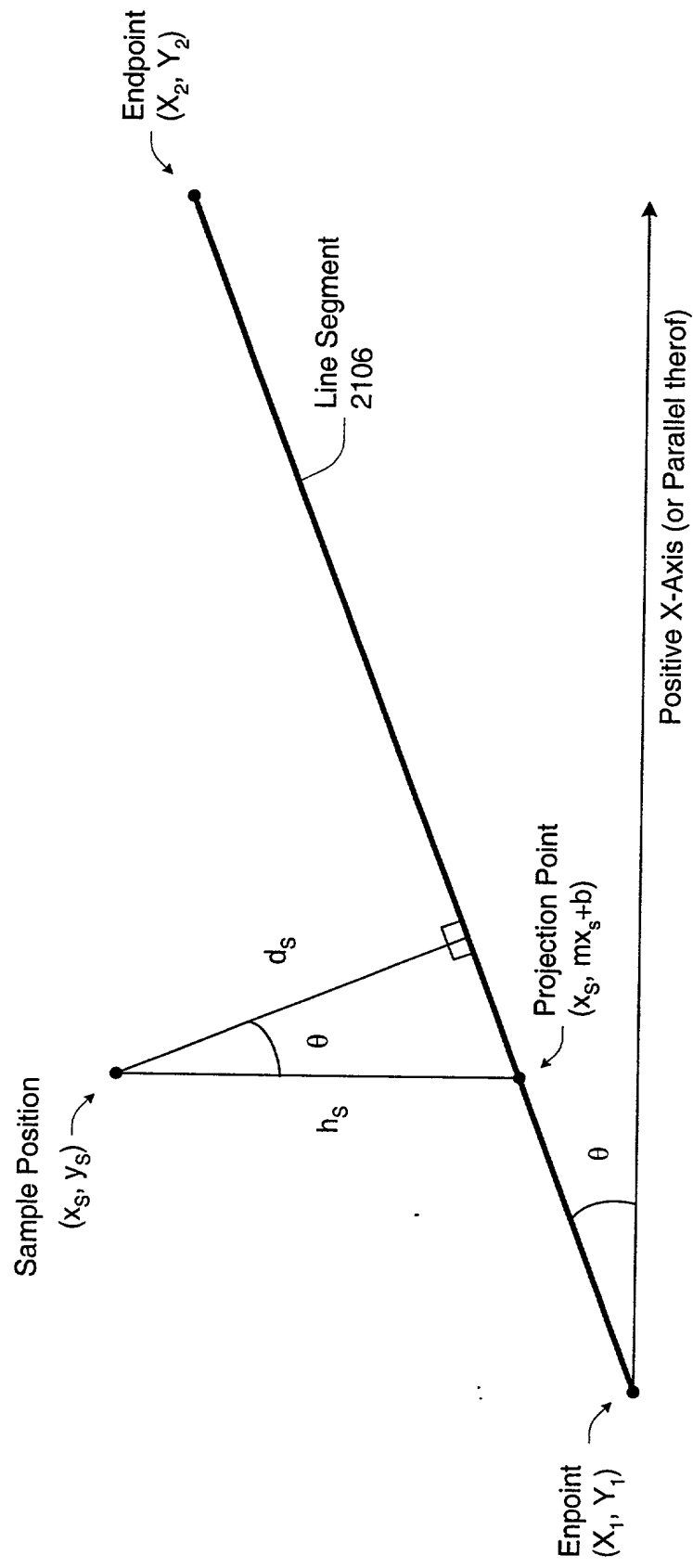


Fig. 17F

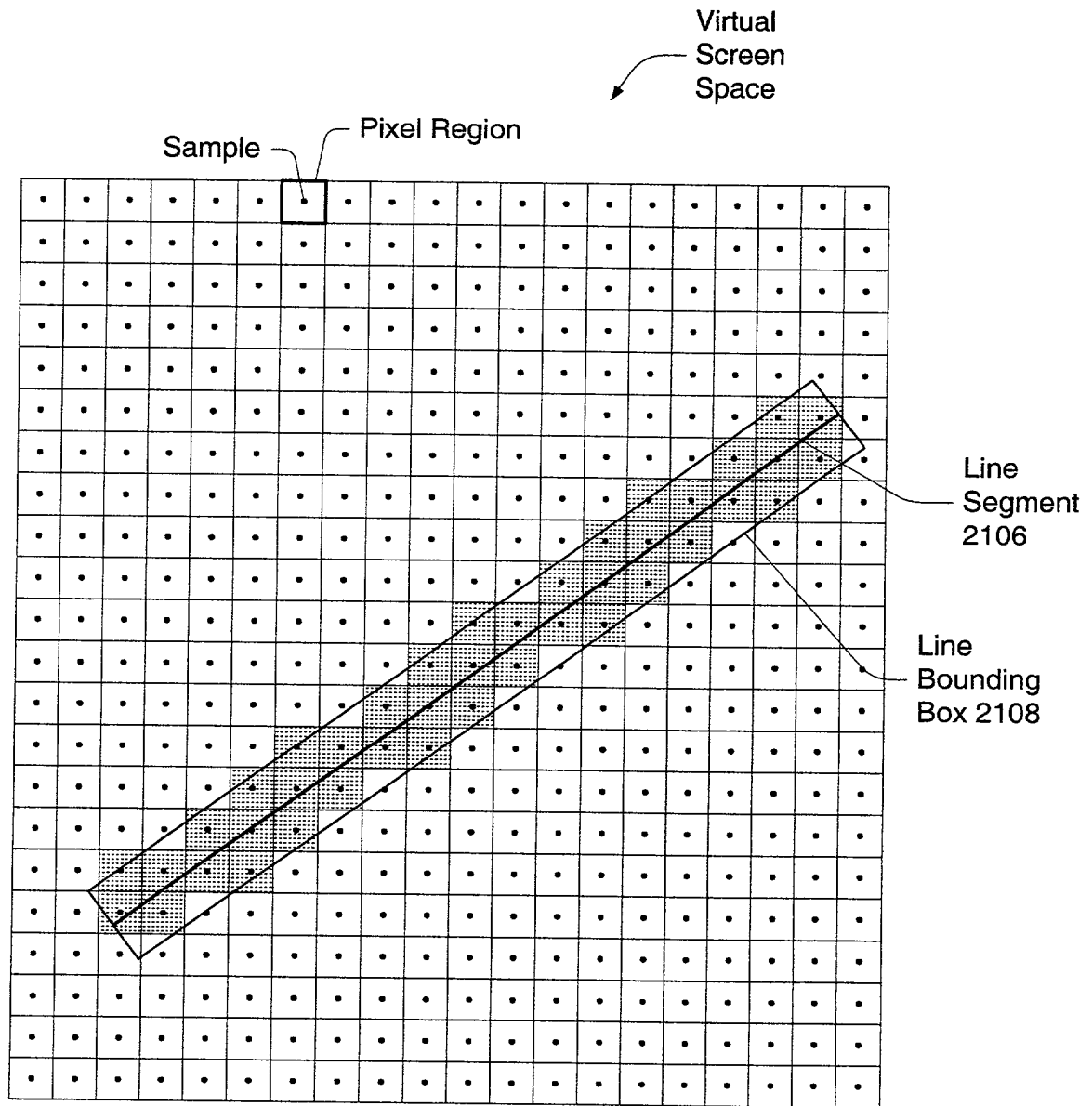


Fig. 18